L Number	Hits	Search Text	DB	Time stamp
3	166485	compar$4 with (data profile static$4)	USPAT	2004/11/29 18:41
4	126167	(identif$5 determin$5 detect$4) with (fail$4 defect$4 fault$4 malfunction$4)	USPAT	2004/11/29 18:42
5	417	thin adj film adj transistor with (fail$4 defect$4 fault$4 malfunction$4)	USPAT	2004/11/29 18:42
6	24538	(compar$4 with (data profile static$4)) and ((identif$5 determin$5 detect$4) with (fail$4 defect$4 fault$4 malfunction$4))	USPAT	2004/11/29 18:42
7	16	(thin adj film adj transistor with (fail$4 defect$4 fault$4 malfunction$4)) and ((compar$4 with (data profile static$4)) and ((identif$5 determin$5 detect$4) with (fail$4 defect$4 fault$4 malfunction$4)))	USPAT	2004/11/29 19:08
8	0	look adj up adj table with (relat$4 correspon$4 associtat$4) with (manufactur$4 fabricat$4 making) with (fail$4 malfunction$4 fault$4 defect$4) with compar$4	USPAT	2004/11/29 19:10
9	0	look adj up adj table same (relat$4 correspon$4 associtat$4) same (manufactur$4 fabricat$4 making) same (fail$4 malfunction$4 fault$4 defect$4) same compar$4	USPAT	2004/11/29 19:11
10	1483	look adj up adj table and (relat$4 correspon$4 associtat$4) and (manufactur$4 fabricat$4 making) and (fail$4 malfunction$4 fault$4 defect$4) same compar$4	USPAT	2004/11/29 19:11
12	0	(thin adj film adj transistor with (fail$4 defect$4 fault$4 malfunction$4)) and (look adj up adj table same (relat$4 correspon$4 associtat$4) same (manufactur$4 fabricat$4 making) and (fail$4 malfunction$4 fault$4 defect$4) with compar$4)	USPAT	2004/11/29 19:12
11	22	look adj up adj table same (relat$4 correspon$4 associtat$4) same (manufactur$4 fabricat$4 making) and (fail$4 malfunction$4 fault$4 defect$4) with compar$4	USPAT	2004/11/29 19:20
13	271	(predefined predetermined) adj3 (defect$4 fail$4 fault$4 malfunction$4) with (profile table classification stored)	USPAT	2004/11/29 19:22
14	2	(thin adj film adj transistor with (fail$4 defect$4 fault$4 malfunction$4)) and ((predefined predetermined) adj3 (defect$4 fail$4 fault$4 malfunction$4) with (profile table classification stored))	USPAT	2004/11/29 19:22
-	14	(thin adj film adj transistor with (manufactur$4 fabricat$4 making)) same ((identif$5 determin$5 detect$4) with (fail$4 defect$4 fault$4 malfunction$4))	USPAT	2004/11/29 18:41
-	7	((thin adj film adj transistor with (manufactur$4 fabricat$4 making)) same ((identif$5 determin$5 detect$4) with (fail$4 defect$4 fault$4 malfunction$4))) and ((apply$4 applies inject$4) and (compar$4 identif$4 determin$4))	USPAT	2004/11/29 14:48
-	1	5546013.pn.	USPAT	2004/11/29 14:48
-	401	(identif$5 determin$5 detect$4) with caus$4 adj3 (fail$4 defect$4 fault$4 malfunction$4) with (manufactur$4 making fabricat$4)	USPAT	2004/11/29 16:11
-	3432	thin adj film adj transistor with (manufactur$4 fabricat$4 making)	USPAT	2004/11/29 16:12
-	7	((identif$5 determin$5 detect$4) with caus$4 adj3 (fail$4 defect$4 fault$4 malfunction$4) with (manufactur$4 making fabricat$4)) and (thin adj film adj transistor with (manufactur$4 fabricat$4 making))	USPAT	2004/11/29 16:12
-	1043811	(apply$4 applies inject$4) and (compar$4 identif$4 determin$4)	USPAT	2004/11/29 16:16